Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination TENGWALL ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2003/0054810 A1	03-2003	Chen et al.	455/422
	В	US-2004/0133520 A1	07-2004	Callas et al.	705/051
	С	US-2002/0059144 A1	05-2002	Meffert et al.	705/51
	D	US-6,680,935 B1	01-2004	Kung et al.	370/352
	E	US-2004/0166834 A1	08-2004	Omar et al.	455/414.1
	F	US-2003/0157947 A1	08-2003	Fiatal et al.	455/466
	G	US-2001/0034225	10-2001	Gupte et al.	455/412
	Н	US-2004/0022237	02-2004	Elliott et al.	370/356
	1	US-2002/0010758	01-2002	Chan, Chung	709/218
	J	US-			
	К	US-			
	L	US-			
	M.	US-			

FOREIGN PATENT DOCUMENTS

*	, 300	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.